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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-3,783,969 A	01-1974	Pall, David B.	181/286
*	В	US-4,048,366 A	09-1977	Kingsbury, Herbert William	428/215
*	C	US-4,142,605 A	03-1979	Bosch, Norbert	181/204
*	D	US-4,416,716 A	11-1983	Ichikawa et al.	156/245
*	Е	US-4,487,289 A	12-1984	Kicinski et al.	181/252
*	F	US-4,522,165 A	06-1985	Ogawa, Naoki	123/195C
*	G	US-5,057,176 A	10-1991	Bainbridge, William	156/222
*	Ι	US-5,134,014 A	07-1992	Zaima et al.	428/186
*	I	US-5,170,019 A	12-1992	Lee, Jung W.	181/204
*	J	US-5,196,253 A	03-1993	Mueller et al.	428/138
*	К	US-5,233,832 A	08-1993	Moore, III, Dan T.	60/323
*	L	US-5,456,291 A	10-1995	Kunzmann, Thomas	138/121
*	М	US-5,464,952 A	11-1995	Shah et al.	181/211

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited Application/Control No. 10/535,350 Applicant(s)/Patent Under Reexamination BERBNER ET AL. Examiner FORREST M. PHILLIPS 2837 Applicant(s)/Patent Under Reexamination BERBNER ET AL. Page 2 of 4

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,503,903 A	04-1996	Bainbridge et al.	428/182
*	В	US-5,550,338 A	08-1996	Hielscher, Peter	181/290
*	С	US-5,590,524 A	01-1997	Moore et al.	60/323
*	D	US-5,633,067 A	05-1997	Illbruck et al.	428/138
*	Е	US-5,670,264 A	09-1997	Sheridan, Steven William	428/594
*	F	US-5,681,072 A	10-1997	Stricker, Klaus	296/39.3
*	G	US-5,680,757 A	10-1997	Pirchl, Gerhard	60/299
*	Η	US-5,756,942 A	05-1998	Tanaka et al.	181/207
*	Ι	US-5,800,905 A	09-1998	Sheridan et al.	428/157
*	J	US-5,866,235 A	02-1999	Fredrick et al.	428/182
*	К	US-5,939,212 A	08-1999	Ragland et al.	428/594
*	L	US-5,968,629 A	10-1999	Masui et al.	428/77
*	М	US-5,996,730 A	12-1999	Pirchl, Gerhard	181/211

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited Application/Control No. 10/535,350 Applicant(s)/Patent Under Reexamination BERBNER ET AL. Examiner FORREST M. PHILLIPS Art Unit Page 3 of 4

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,026,846 A	02-2000	Wolf et al.	137/375
*	В	US-6,186,270 B1	02-2001	Roller et al.	181/286
*	O	US-6,196,488 B1	03-2001	Sakata et al.	242/388
*	D	US-6,302,466 B1	10-2001	Zwick, Evelyn	296/39.3
*	Е	US-6,465,110 B1	10-2002	Boss et al.	428/608
*	F	US-2002/0185893 A1	12-2002	Hashirayama et al.	296/204
*	G	US-6,586,111 B2	07-2003	Ragland et al.	428/593
*	Ι	US-6,647,715 B2	11-2003	Farkas, Kornel	60/323
*	-	US-2004/0041428 A1	03-2004	Tompson, Graham	296/039.3
*	٦	US-2004/0166296 A1	08-2004	Ragland et al.	428/209
*	K	US-6,821,607 B2	11-2004	Zwick et al.	428/172
*	L	US-6,823,571 B1	11-2004	Ragland et al.	29/17.4
*	М	US-2004/0238276 A1	12-2004	Matias et al.	181/290

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited Application/Control No. 10/535,350 Examiner FORREST M. PHILLIPS Applicant(s)/Patent Under Reexamination BERBNER ET AL. Page 4 of 4

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2005/0139416 A1	06-2005	Niwa et al.	181/207
*	В	US-2005/0133302 A1	06-2005	Pfaffelhuber et al.	181/293
*	С	US-6,966,402 B2	11-2005	Matias et al.	181/290
*	D	US-2005/0263346 A1	12-2005	Nishimura, Yasuhiko	181/290
*	Е	US-2006/0037809 A1	02-2006	Fuller et al.	181/207
*	F	US-2006/0124387 A1	06-2006	Berbner et al.	181/290
*	O	US-2007/0034446 A1	02-2007	Proscia et al.	181/290
*	I	US-2007/0137926 A1	06-2007	Albin et al.	181/290
	Ι	US-			
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FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

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A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.